

Aeris- PANalytical's new benchtop XRD with best in class performance

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Materials research is everywhere – from pharmaceuticals to geological exploration to research on the latest nanomaterials. In all these fields X-ray diffraction (XRD) can be a key tool to determine structure as related to physical properties. PANalytical's new benchtop X-ray diffractometer, Aeris, has been designed for easy everyday analysis of materials. Yet, the performance of the instrument is what previously would only have been expected from a full-power, large, floor-standing X-ray diffraction system. Aeris' sample handling is very flexible, as it can accommodate many types of sample holders in its external sample changer, and is suitable for automation by robots or belts. In this presentation we will show the performance, power and ease of use of the Aeris.

